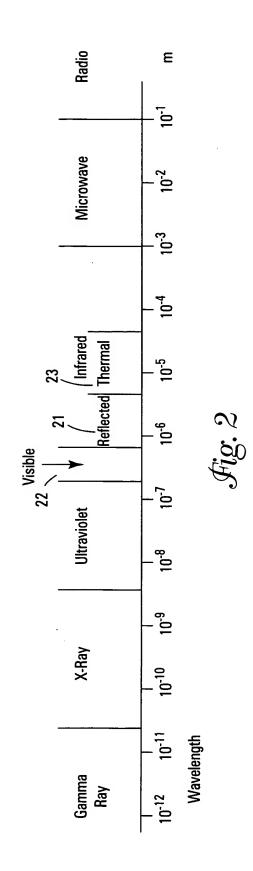
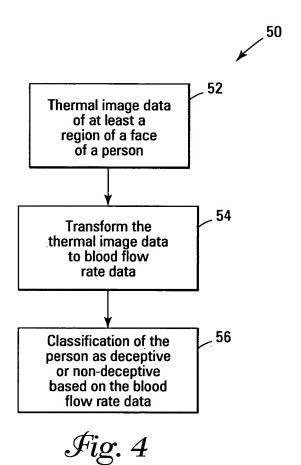


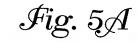
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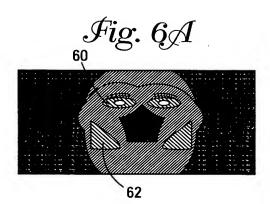
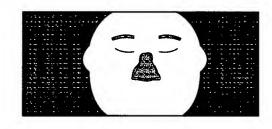
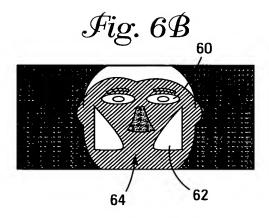
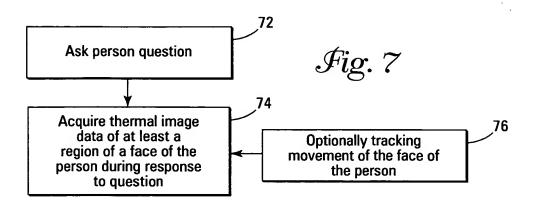


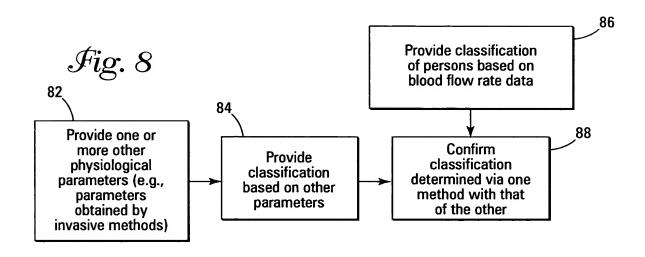
Fig. 5B

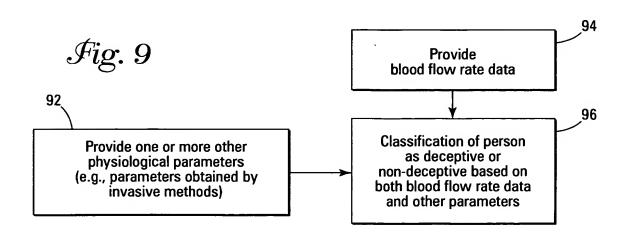


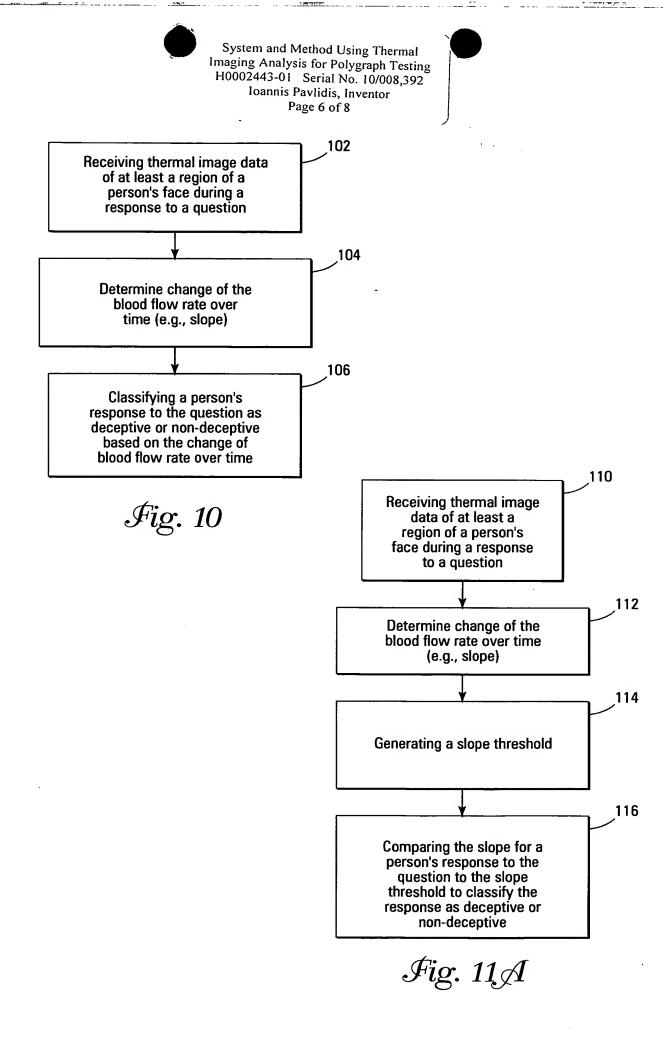


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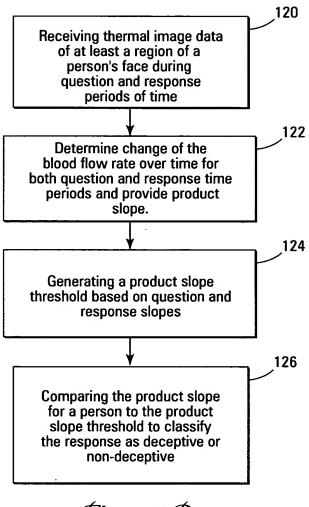


Fig. 11 B

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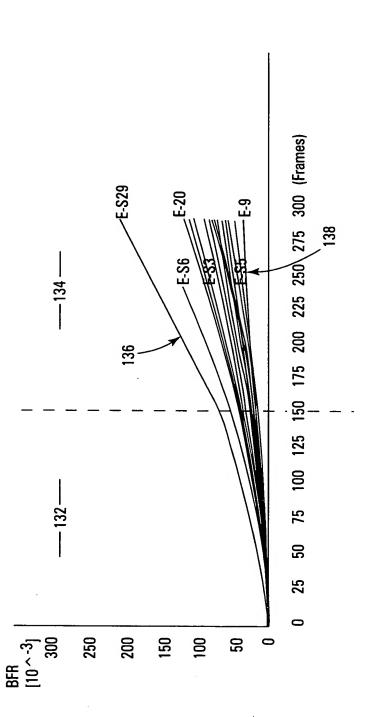


Fig. 12